

# ELECTRONIC INFORMATION DISCLOSURE STATEMENT

Electronic Version v18

Stylesheet Version v18.0

## Title of Invention

STRUCTURE FOR MEASUREMENT OF CAPACITANCE OF  
ULTRA-THIN DIELECTRICS

Application Number :

Confirmation Number:

First Named Applicant: Edward Maciejewski

Attorney Docket Number: BUR920030052US1

Art Unit:

Examiner:

Search string: ( 4795964 or 6133746 or 6456105 or 6472233 or 6476632 ).pn

## US Patent Documents

Note: Applicant is not required to submit a paper copy of cited US Patent Documents

init	Cite.No.	Patent No.	Date	Patentee	Kind	Class	Subclass
<i>mk</i>	1	4795964	1989-01-03	Mahant-Shetti et al.			
<i>mk</i>	2	6133746	2000-10-17	Fang et al.			
<i>mk</i>	3	6456105	2002-09-24	Tao			
<i>mk</i>	4	6472233	2002-10-29	Ahmed et al.			
<i>mk</i>	5	6476632	2002-11-05	La Rosa et al.			

## Signature

Examiner Name	Date
<i>Maria Hramshaya</i>	<i>12/20/09</i>

# INFORMATION DISCLOSURE CITATION

(Use several sheets if necessary)

Docket Number (Optional)

BUR920030052US1

Application Number

Not Yet Assigned

Applicant(s)

Nowak et al.

Filing Date

Concurrently Herewith

Group Art Unit

Not Yet Assigned

## U.S. PATENT DOCUMENTS

*EXAMINER INITIAL	REF	DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE

## FOREIGN PATENT DOCUMENTS

REF	DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	Translation	
						YES	NO

## OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, Etc.)

MK		"A Simple Method for On-Chip, Sub-Femto Farad Interconnect Capacitance Measurement", Bruce W. McGaughy, James C. Chen, Dennis Sylvester, Cheuming Hu, IEEE, Vol. 18, No. 1, January 1997, 1 page

EXAMINER

Manna Kramshaya

DATE CONSIDERED

12/2004

EXAMINER: Initial if citation considered, whether or not citation is in conformance with MPEP Section 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.